2-Propanol CMOS

(iso-propyl alcohol)



Material No.: 9059-08 Batch No.: 0000223924

Manufactured Date: 2019/02/01 Retest Date: 2024/01/31

Revision No: 1

Certificate of Analysis

| Test | Specification | Result |
|--|---------------|--------|
| Assay (CH ₃ CHOHCH ₃) | >= 99.5 % | 100.0 |
| Color (APHA) | <= 10 | < 5 |
| Residue after Evaporation | <= 4 ppm | 2 |
| Solubility in H₂O | Passes Test | PT |
| Water (H2O)(by Karl Fischer titrn) | <= 0.05 % | 0.01 |
| Acidity (µeq/g) | <= 0.2 | 0.1 |
| Alkalinity (µeq/g) | <= 0.1 | < 0.1 |
| Chloride (Cl) | <= 0.1 ppm | < 0.1 |
| Phosphate (PO ₄) | <= 0.3 ppm | < 0.3 |
| Trace Impurities – Aluminum (Al) | <= 50.0 ppb | < 5.0 |
| Arsenic and Antimony (as As) | <= 10 ppb | < 10 |
| Trace Impurities – Barium (Ba) | <= 20.0 ppb | < 1.0 |
| Trace Impurities – Beryllium (Be) | <= 100.0 ppb | < 1.0 |
| Trace Impurities - Bismuth (Bi) | <= 100.0 ppb | < 10.0 |
| Trace Impurities – Boron (B) | <= 10.0 ppb | < 5.0 |
| Trace Impurities - Cadmium (Cd) | <= 20.0 ppb | < 1.0 |
| Trace Impurities - Calcium (Ca) | <= 50.0 ppb | < 1.0 |
| Trace Impurities - Chromium (Cr) | <= 20.0 ppb | < 1.0 |
| Trace Impurities - Cobalt (Co) | <= 20.0 ppb | < 1.0 |
| Trace Impurities - Copper (Cu) | <= 10.0 ppb | < 1.0 |
| Trace Impurities - Gallium (Ga) | <= 50.0 ppb | < 1.0 |
| Trace Impurities – Germanium (Ge) | <= 50.0 ppb | < 10.0 |
| Trace Impurities – Gold (Au) | <= 20.0 ppb | < 5.0 |
| Heavy Metals (as Pb) | <= 200 ppb | < 100 |

Material No.: 9059-08 Batch No.: 0000223924

| Test | Specification | Result |
|--|---------------|--------|
| Trace Impurities – Iron (Fe) | <= 50.0 ppb | < 1.0 |
| Trace Impurities - Lead (Pb) | <= 20.0 ppb | < 10.0 |
| Trace Impurities - Lithium (Li) | <= 50.0 ppb | < 1.0 |
| Trace Impurities – Magnesium (Mg) | <= 20.0 ppb | < 1.0 |
| Trace Impurities - Manganese (Mn) | <= 15.0 ppb | < 1.0 |
| Trace Impurities - Molybdenum (Mo) | <= 100.0 ppb | < 5.0 |
| Trace Impurities - Nickel (Ni) | <= 10.0 ppb | < 5.0 |
| Trace Impurities - Niobium (Nb) | <= 100.0 ppb | < 1.0 |
| Trace Impurities – Potassium (K) | <= 100.0 ppb | < 10.0 |
| Trace Impurities - Silicon (Si) | <= 50.0 ppb | < 10.0 |
| Trace Impurities – Silver (Ag) | <= 20.0 ppb | < 1.0 |
| Trace Impurities - Sodium (Na) | <= 100.0 ppb | < 5.0 |
| Trace Impurities – Strontium (Sr) | <= 20.0 ppb | < 1.0 |
| Trace Impurities - Tantalum (Ta) | <= 100.0 ppb | < 5.0 |
| Trace Impurities - Thallium (TI) | <= 10.0 ppb | < 5.0 |
| Trace Impurities - Tin (Sn) | <= 100.0 ppb | < 10.0 |
| Trace Impurities - Titanium (Ti) | <= 20.0 ppb | < 1.0 |
| Trace Impurities - Vanadium (V) | <= 100.0 ppb | < 1.0 |
| Trace Impurities – Zinc (Zn) | <= 50.0 ppb | < 1.0 |
| Trace Impurities – Zirconium (Zr) | <= 100.0 ppb | < 1.0 |
| Particle Count at point of fill – 0.5 µm and greater (Rion KS42AF) | <= 150 par/ml | 12 |
| Particle Count at point of fill – 1.0 µm and greater (Rion KS42AF) | <= 25 par/ml | 3 |

For Microelectronic Use

Country of Origin: US

Packaging Site: Paris Mfg Ctr & DC

